

Search Notes

Application/Control No.

10/780,930

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
<i>Text search only see "rpt prout"</i>		<i>TSE</i>